



Equipment List

| Image | Product | Description |
|------------------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-------------------------------------------|
|  | <p>Fluorescence microscope Olympus IX71 <i>Optical Resolution Microscopy & Micro-spectrometry</i></p>  | <p>Inverse epifluorescence microscope</p> |
|  | <p>FTIR IN10 <i>Optical Resolution Microscopy & Micro-spectrometry</i></p>  | <p>FTIR coupled with microscope</p> |
|  | <p>Infra Red Spectrometer <i>Optical Resolution Microscopy & Micro-spectrometry</i></p>  | <p>IR</p> |
|  | <p>Olympus AX70/Provis <i>Optical Resolution Microscopy & Micro-spectrometry</i></p>  | <p>Optical microscope</p> |

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|  | <p>RAMAN <i>Optical Resolution Microscopy & Micro-spectrometry</i></p>  | <p>RAMAN</p> |
|  | <p>Cryo-ultra microtome Reichert 1 <i>Sample Preparation</i></p>  | <p>ultramicrotome</p> |
|  | <p>Cryo-ultra microtome Reichert 2 <i>Sample Preparation</i></p>  | <p>ultra microtome</p> |
|  | <p>Sputter (Carbon) <i>Sample Preparation</i></p>  | <p>sputter</p> |
|  | <p>Sputter (Metal) <i>Sample Preparation</i></p>  | <p>chromium or gold or platine/palladium</p> |
|  | <p>JEOL 7600F <i>Scanning Electron Microscopy (SEM)</i></p>  | <p>Scanning electron microscope. Semi-Inlens secondary electron detector. Lateral secondary electron. Backscattered electron detectors (classical and LABE). EDX analysis. Nanolithography.</p> |

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|  | <p>LEO 982 Scanning Electron Microscopy (SEM)</p>  | <p>Scanning electron microscope. InLens secondary electron detector. Lateral secondary electron detector.</p> |
|  | <p>Agilent 5500 Scanning Probe Microscopy</p>  | <p>Multimode Scanning Probe Microscope</p> |
|  | <p>Bruker Icon Dimension Scanning Probe Microscopy</p>  | <p>Multimode Scanning Probe Microscope</p> |
|  | <p>Bruker Multimode Nanoscope VIII Boltzmann Scanning Probe Microscopy</p>  | <p>Multimode Scanning Probe Microscope</p> |
|  | <p>Bruker Multimode Nanoscope VIII Carnoy Scanning Probe Microscopy</p>  | <p>Multimode Scanning Probe Microscope</p> |

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|  | <p>LEO 922 <i>Transmission Electron Microscopy (TEM)</i></p>  | <p>TEM, STEM, EDX, DRX, EELS</p> |

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